



US00D344464S

**United States Patent** [19]  
**Kerschner et al.**

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[45] **Date of Patent: \*\* Feb. 22, 1994**

[54] **CAPACITIVE TEST PROBE**

[56]

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[75] **Inventors: Ronald K. Kerschner; Lisa M. Kent,**  
both of Loveland, Colo.

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[\*\*] **Term: 14 Years**

[57]

**CLAIM**

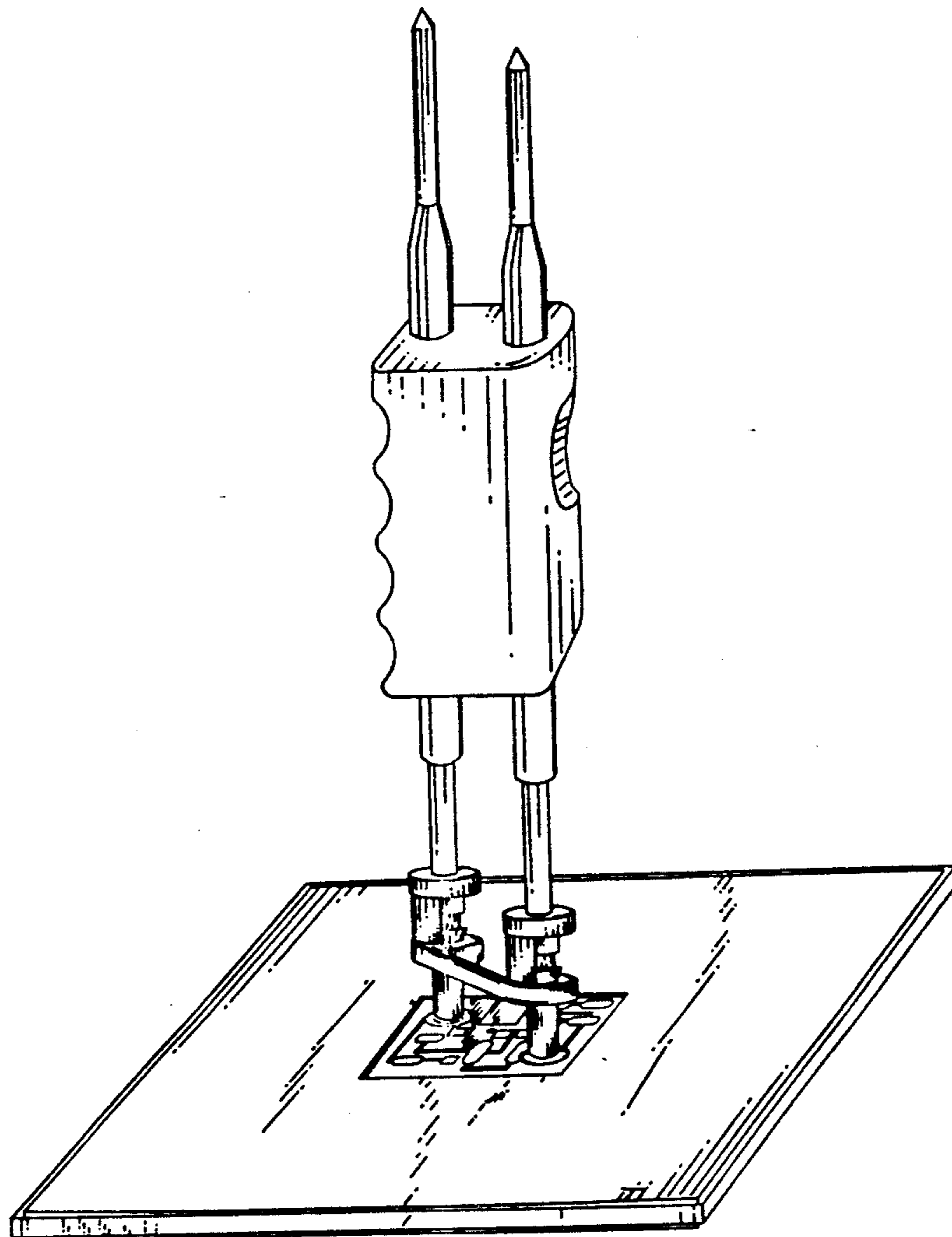
The ornamental design for a capacitive test probe, as shown and described.

[21] **Appl. No.: 1,954**

**DESCRIPTION**

[22] **Filed: Nov. 25, 1992**  
[52] **U.S. Cl. .... D10/80**  
[58] **Field of Search .... 29/401; 73/864.01;**  
324/72.5, 158 F, 158 P, 537, 678, 690; D10/74,  
80; D13/199

FIG. 1 is a top, front perspective view of a capacitive test probe showing our new design;  
FIG. 2 is a top plan view thereof;  
FIG. 3 is a rear elevation view thereof;  
FIG. 4 is a front elevation view thereof;  
FIG. 5 is a left side elevation view thereof;  
FIG. 6 is a right side elevation view thereof; and,  
FIG. 7 is a bottom plan view thereof.



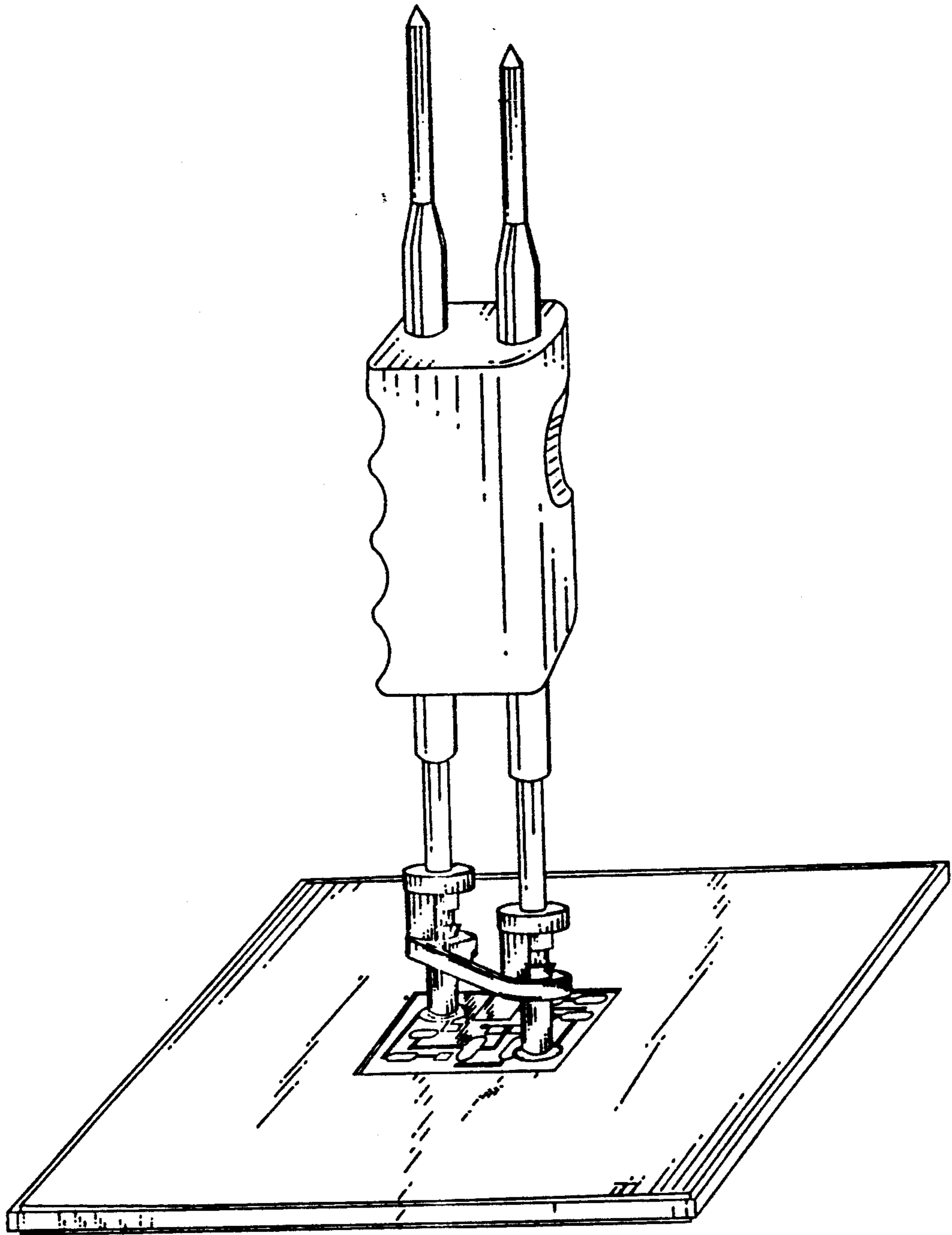


FIG 1

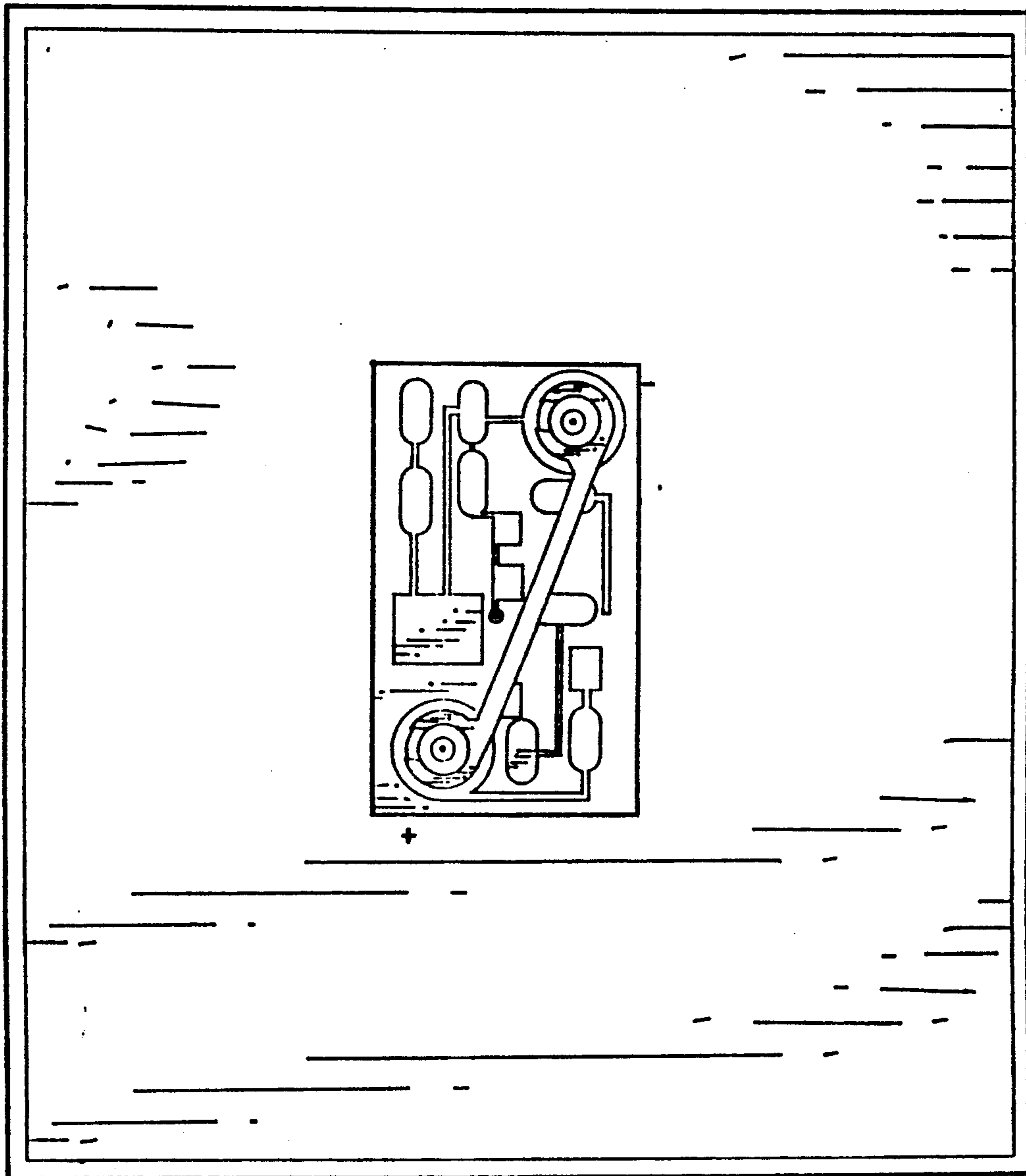


FIG 2

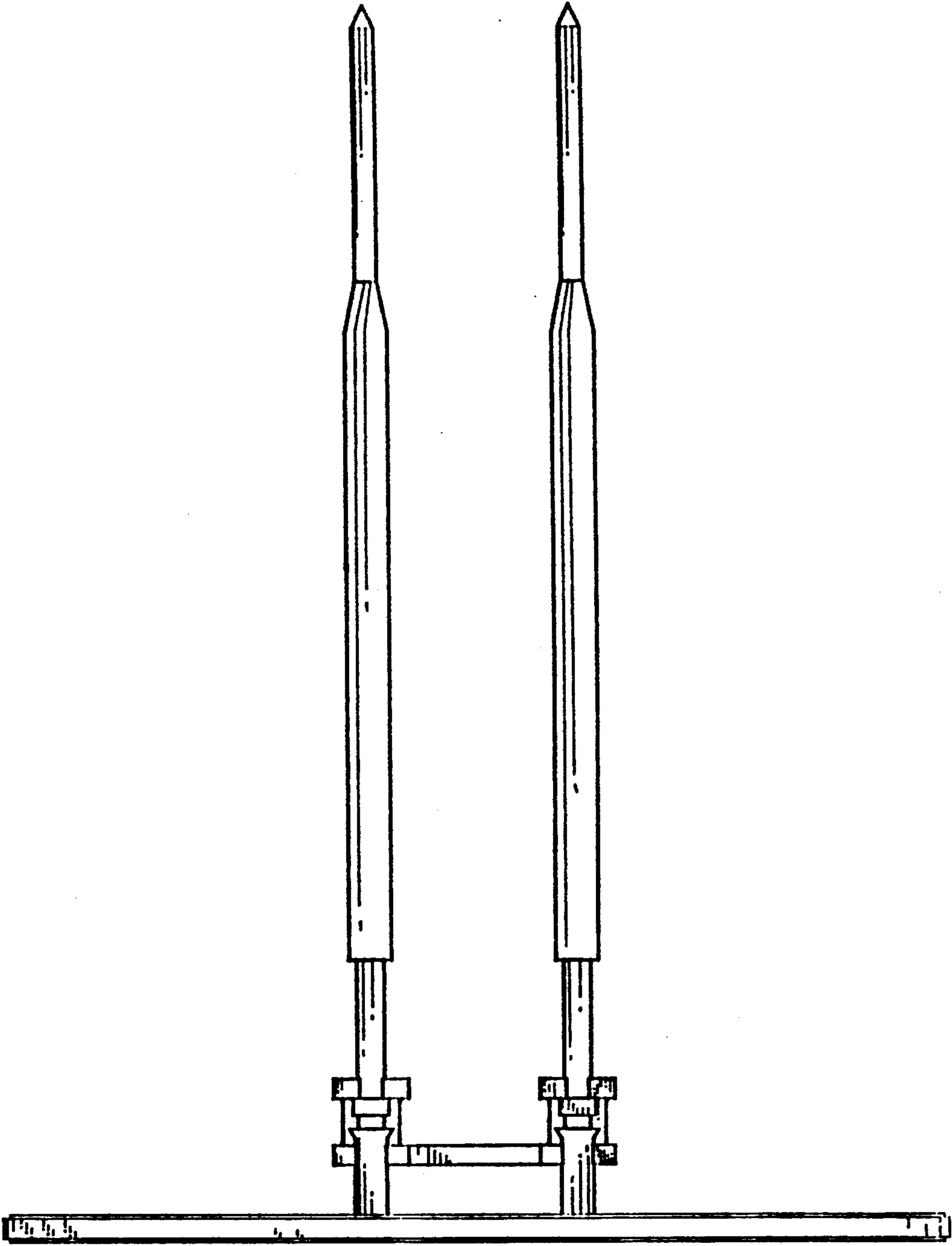


FIG 3.

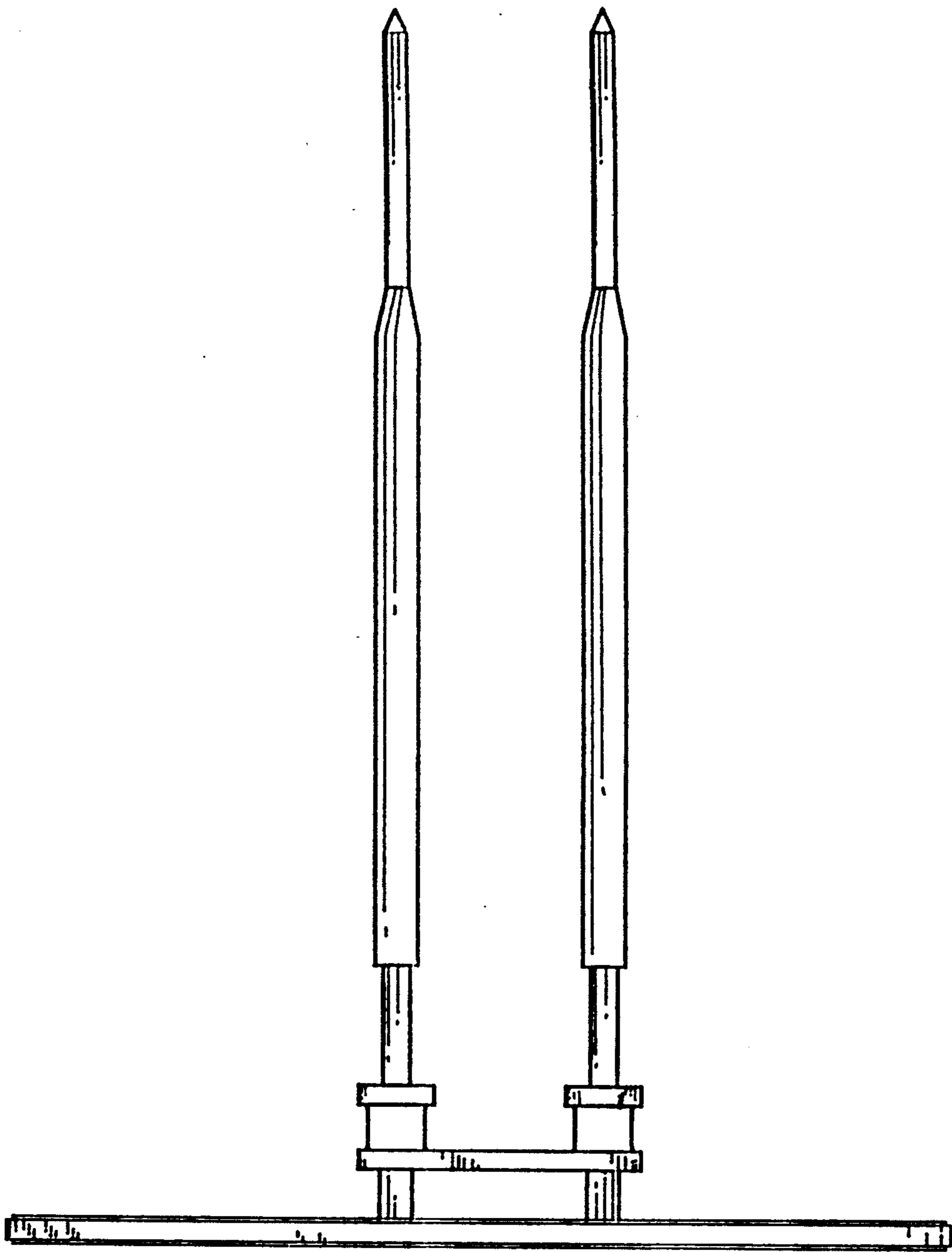


FIG 4

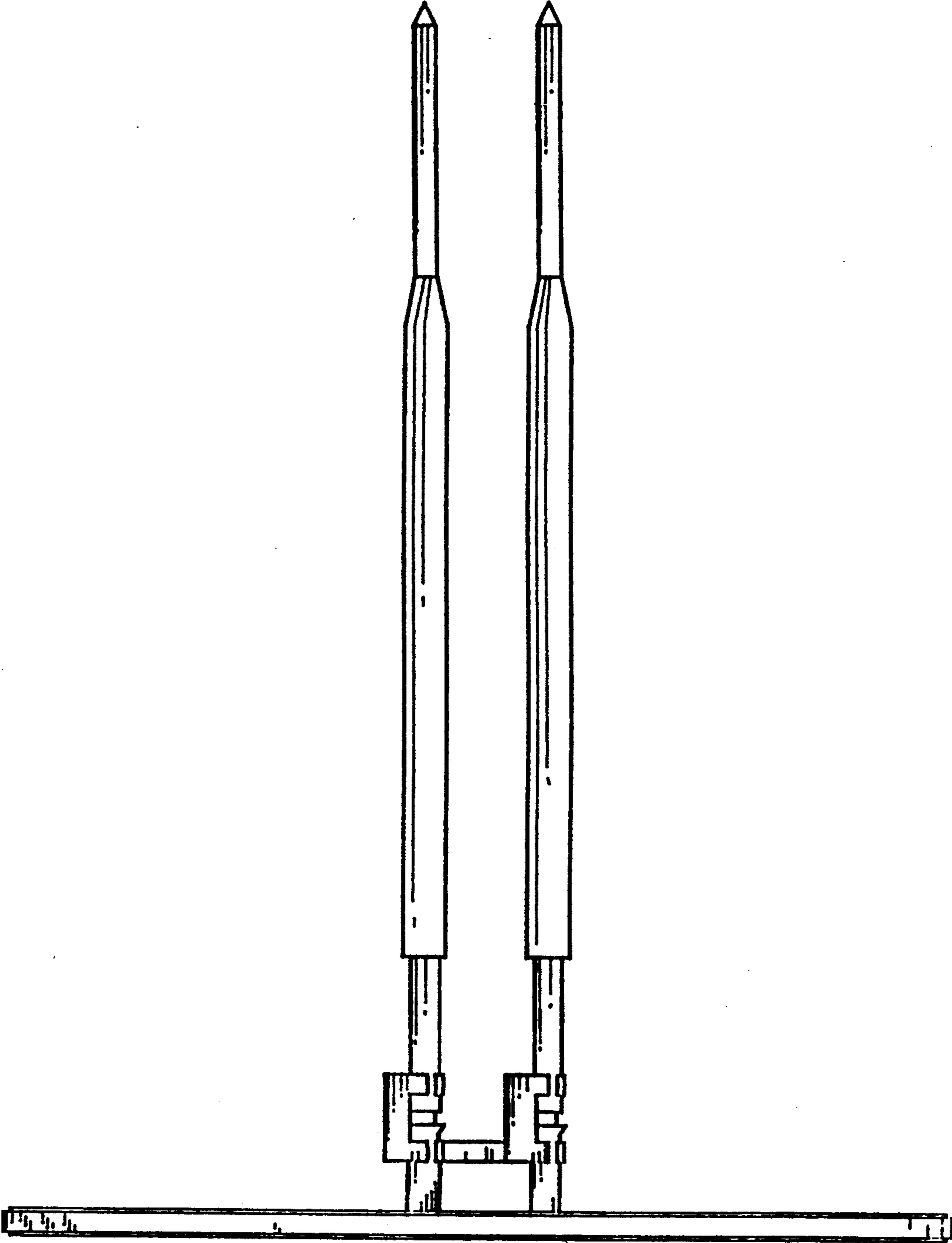


FIG 5

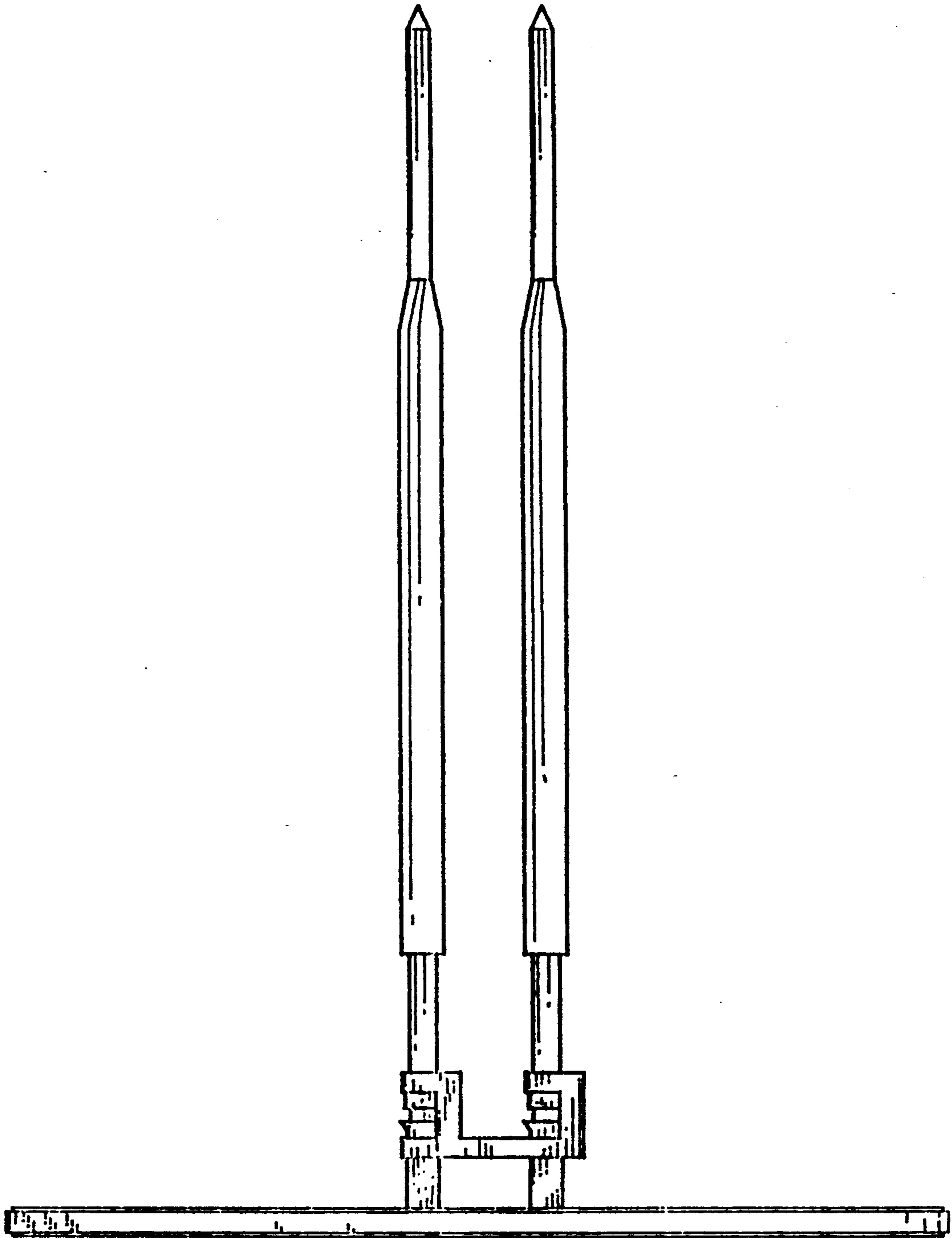


FIG 6

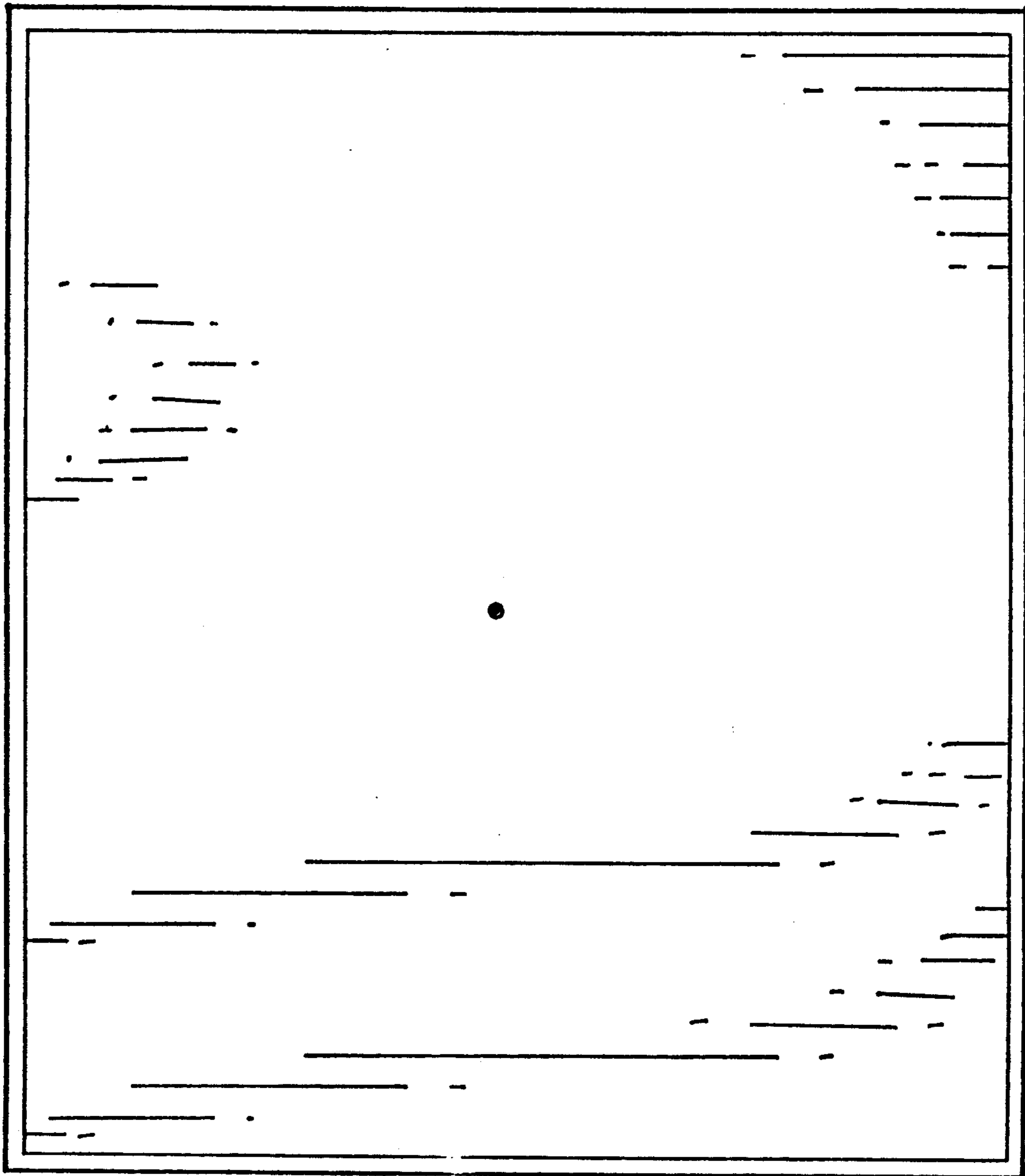


FIG 7